

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of the Claims:

1-10. (canceled)

21. (currently amended) A testing system for testing a plurality of integrated circuit devices; comprising

a tester having an operating frequency;

a board adapted to accommodate a plurality of integrated circuit devices to be tested;

a plurality of integrated circuit device under test (DUT) on the board, each DUT having a voltage controlled oscillator (VCO) circuit and an operating frequency;

~~a plurality of clock circuits, each generating a operating frequency for a DUT;~~

~~a plurality of phase an external comparator device associated with each DUT devices affixed on the tester;~~

~~each phase comparator device having~~

a pair of input terminals adapted to receiving the operating frequency of the tester and the operating frequency of a DUT, and

an output terminal adapted to transmitting a signal indicative of a difference between the operating frequencies of the tester and the DUT; and

~~each clock circuit including a the~~ voltage controlled oscillator (VCO) circuit operable to adjust the DUT operating frequency based on the output signal of the phase comparator device.

22-23. (canceled)

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Amdt. dated January 4, 2006
Reply to Office action of November 7, 2005

24. (previously presented) The testing system of claim 21, in which the comparator is a part of a PLL circuit, which further comprises a low pass filter and an amplifier.
25. (previously presented) The testing system of claim 24, in which the VCO circuit is coupled to the amplifier.